



## OPTO-EDU A63.7010 EBL Electron Beam Lithography Machine

### Our Product Introduction

for more products please visit us on [cnoec.com](http://cnoec.com)

#### Basic Information

- Place of Origin: China
- Brand Name: CNOEC, OPTO-EDU
- Certification: CE,
- Model Number: A63.7010
- Minimum Order Quantity: 1 pc
- Price: FOB \$1~1000, Depend on Order Quantity
- Packaging Details: Carton Packing, For Export Transportation
- Delivery Time: 180 Days
- Payment Terms: T/T, West Union, Paypal
- Supply Ability: 5000 pcs/ Month



#### Product Specification

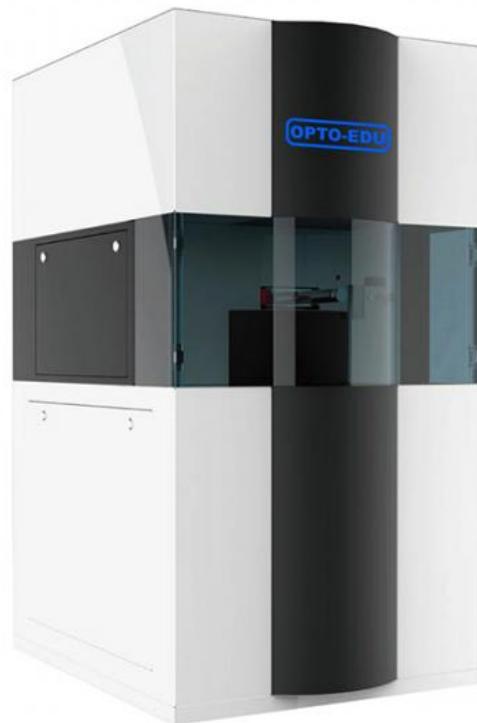
- Standard Equipment: Laser Interferometer Stage
- Stage Travel: ≤105 Mm
- Image Resolution: ≤1nm@15kV; ≤1.5nm@1kV
- Beam Current Densit: >5300 A/cm<sup>2</sup>
- Minimum Beam Spot Size: ≤2 Nm
- Electron Beam Shutter: Rise Time < 100 Ns
- Highlight: **EBL electron beam lithography machine, electron beam lithography scanning microscope, OPTO-EDU A63.7010 lithography machine**

### Product Description



## A63.7010

### EBL Electron Beam Lithography Machine

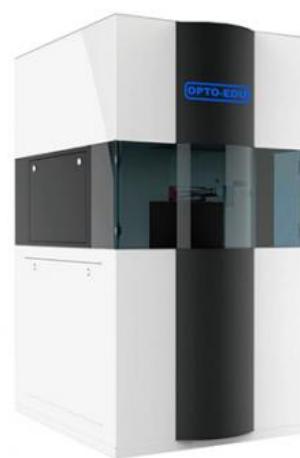


### A63.7010 Specification



#### Technical Features

The A63.7010 electron beam lithography system(EBL) utilizes a field emission gun and is equipped with an integrated high-speed graphics generator to achieve high-speed, high-resolution lithography on semiconductor wafers. The system comes standard with a high-precision laser interferometer-based stage, allowing users to meet the demands of large-stroke, high-precision stitching and overlay. This system plays a significant role in the fields of new materials, cutting-edge physics research, semiconductors, microelectronics, photonics, and quantum research.



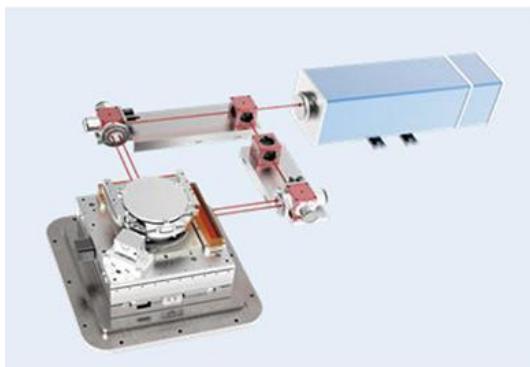
#### Stage Specifications

Standard Equipment	Laser Interferometer Stage
Stage Travel	≤105 mm

Electron Gun and Imaging Specifications	
Schottky Field Emission Gun	Acceleration Voltage 20V~30kV/Side Secondary Electron Detector and In-Lens Electron Detector
Image Resolution	$\leq 1\text{nm}@15\text{kV}; \leq 1.5\text{nm}@1\text{kV}$
Beam Current Density	$>5300\text{ A/cm}^2$
Minimum Beam Spot Size	$\leq 2\text{ nm}$
Lithography Specifications	
Electron Beam Shutter	Rise Time $< 100\text{ ns}$
Writing Field	$\leq 500\times 500\text{ um}$
Minimum Single Exposure Line Width	$10\pm 2\text{nm}$
Scan Speed	25 MHz/ 50 MHz
Graphics Generator Parameters	
Control Core	High-performance FPGA
Maximum Scan speed	50 MHz
D/A Resolution	20-bit
Supported Writing Field Sizes	10 um~500 um
Beam Shutter Support	5V TTL
Minimum Dwell Time Increment	10ns
Supported File Formats	GDSII, DXF, BMP, etc.
Faraday Cup Beam Current Measurement	Included
Proximity Effect Correction	Optional
Laser Interferometer Stage	Optional
Scan Modes	Sequential (Z-type), Serpentine (S-type), Spiral, and other vector scan modes
Exposure Modes	Supports field calibration, field stitching, overlay, and multi-layer automatic exposure
External Channel Support	supports electron beam scanning, stage movement, beam shutter control, and secondary electron detection

## A63.7010 Product Features

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### Laser Interferometer Stage

Laser Interferometer Stage: An advanced laser interferometer stage that meets the requirements for large-stroke, high-precision stitching and overlay

### Field Emission Gun

A high-resolution field emission gun is an important guarantee for lithography quality





#### Graphics Generator

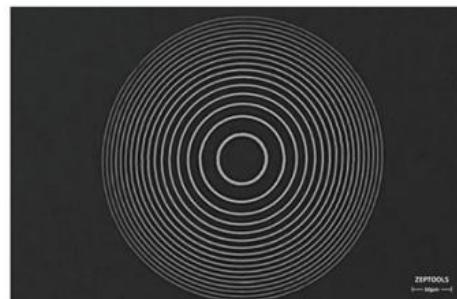
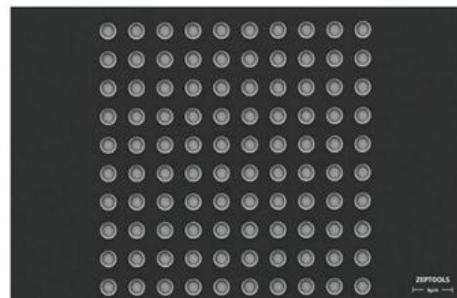
Achieves ultra-high resolution pattern drawing while ensuring ultra-high-speed scanning

A63.7010 VS Raith 150 Two		
Device Model	OPTO-EDU A63.7010 (China)	Raith 150 Two (Germany)
Acceleration Voltage (kV)	30	30
Min. Beam SpotDiameter (nm)	2	1.6
Stage Size (inch)	4	4
Minimum Linewidth (nm)	10	8
Stitching Accuracy (nm)	50(35nm)	35
Overlay Accuracy (nm)	50(35nm)	35

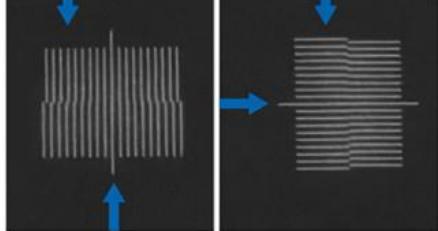
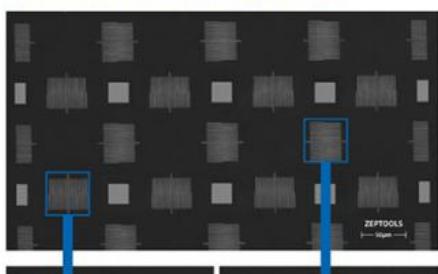
#### A63.7010 Application

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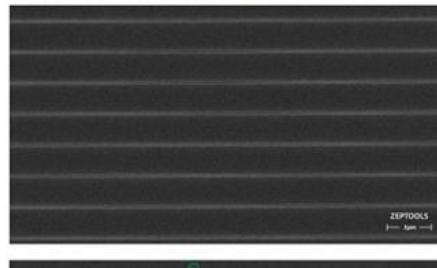
##### ♦ Uniformity Test



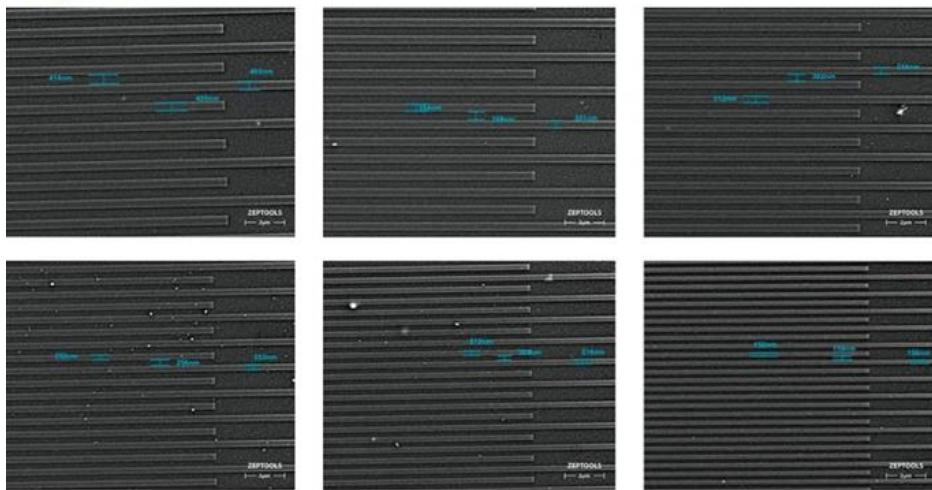
##### ♦ Field Stitching (Measurement With Vernier Caliper)



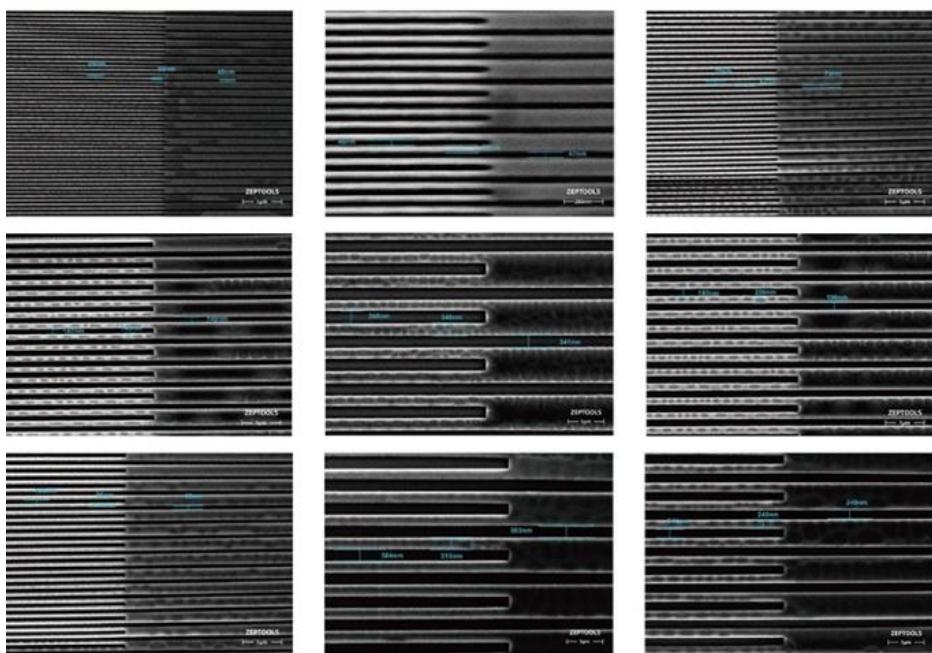
##### ♦ Minimum Linewidth Test



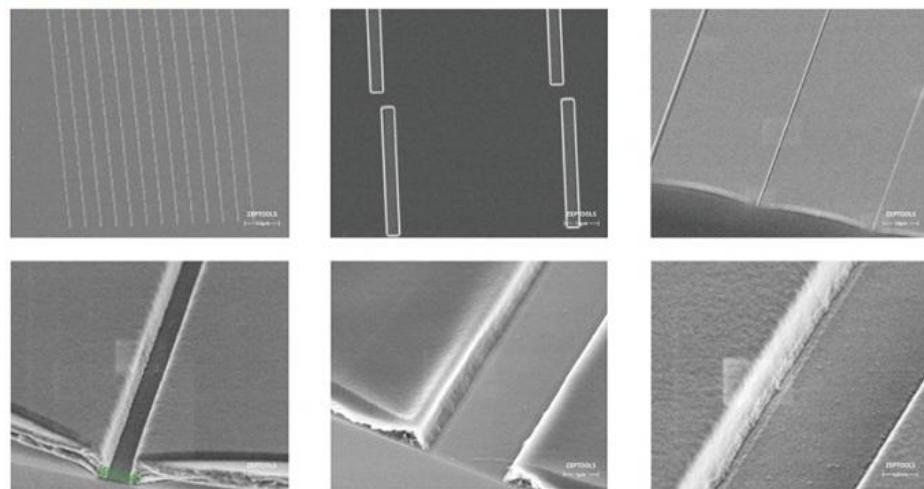
◆ HSQ Resist Test



◆ PMMA Resist Test



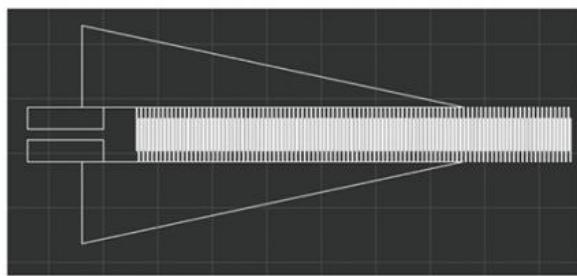
◆ Thick Resist Test



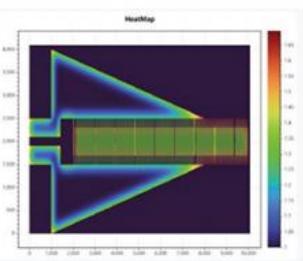
◆ Seamless Stitching Of Long Gratings



◆ Proximity Effect Correction • Dose Correction Effect

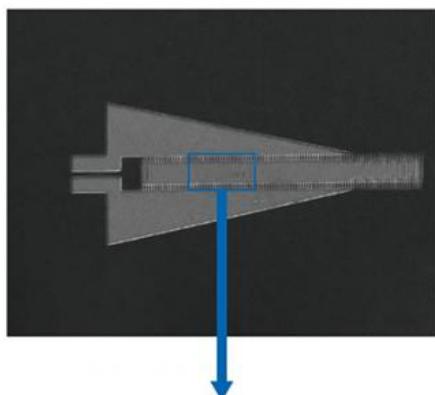


Design Model (The Width Of The Groove Is 200 nm)

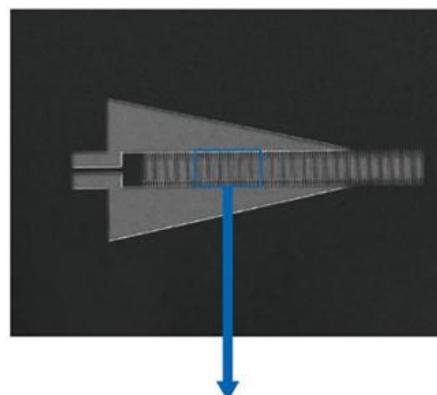


Dosage Correction Results

◆ Comparison Before And After Dosage Correction



Exposure Results Without Dosage Correction



Exposure Results With Dosage Correction



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